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Application/Control No.	Applicant(s)/Patent under Reexamination BLAICHER, CHRISTOPHER Y.	
10/618,500		
Examiner	Art Unit	
Usmaan Saeed	2166	

	SEAR	CHED	
Class	Subclass	Date	Examiner
707	7	1/20/2006	US
707	101	1/20/2006	US
707	102	1/20/2006	US

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
				
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Inventor & related case search	1/5/2006	US	
East (US-PGPUB, USPAT, USOCR, EPO, JPO, DERWENT, IBM_TDB)	1/6/2006	US	
Consulted Primary Examiner (Leslie Wong)	1/6/2006	US	
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